

SN74107, SN74LS107A,
SN74107, SN74LS107A
DUAL J-K FLIP-FLOPS WITH CLEAR
 DECEMBER 1983 — REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

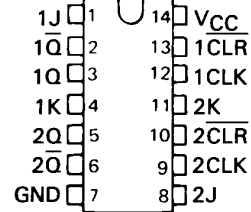
description

The '107 contain two independent J-K flip-flops with individual J-K, clock, and direct clear inputs. The '107 is a positive pulse-triggered flip-flop. The J-K input data is loaded into the master while the clock is high and transferred to the slave and the outputs on the high-to-low clock transition. For these devices the J and K inputs must be stable while the clock is high.

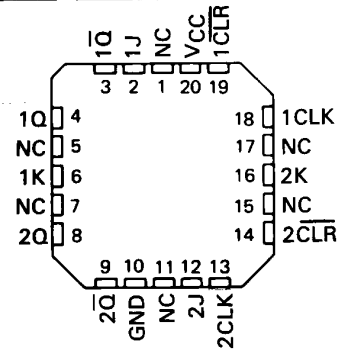
The 'LS107A contain two independent negative-edge-triggered flip-flops. The J and K inputs must be stable prior to the high-to-low clock transition for predictable operation. When the clear is low, it overrides the clock and data inputs forcing the Q output low and the \bar{Q} output high.

The SN54107 and the SN54LS107A are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74107 and the SN74LS107A are characterized for operation from 0°C to 70°C.

SN54107, SN54LS107A . . . J PACKAGE
 SN74107 . . . N PACKAGE
 SN74LS107A . . . D OR N PACKAGE
 (TOP VIEW)



SN54LS107A . . . FK PACKAGE
 (TOP VIEW)



NC - No internal connection

'107
 FUNCTION TABLE

INPUTS				OUTPUTS	
\bar{CLR}	CLK	J	K	Q	\bar{Q}
L	X	X	X	L	H
H	\downarrow	L	L	Q_0	\bar{Q}_0
H	\downarrow	H	L	H	L
H	\downarrow	L	H	L	H
H	\downarrow	H	H	TOGGLE	
H	H	X	X	Q_0	\bar{Q}_0

'LS107A
 FUNCTION TABLE

INPUTS				OUTPUTS	
\bar{CLR}	CLK	J	K	Q	\bar{Q}
L	X	X	X	L	H
H	\downarrow	L	L	Q_0	\bar{Q}_0
H	\downarrow	H	L	H	L
H	\downarrow	L	H	L	H
H	\downarrow	H	H	TOGGLE	
H	H	X	X	Q_0	\bar{Q}_0

HEADINGS—UNIVERS

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PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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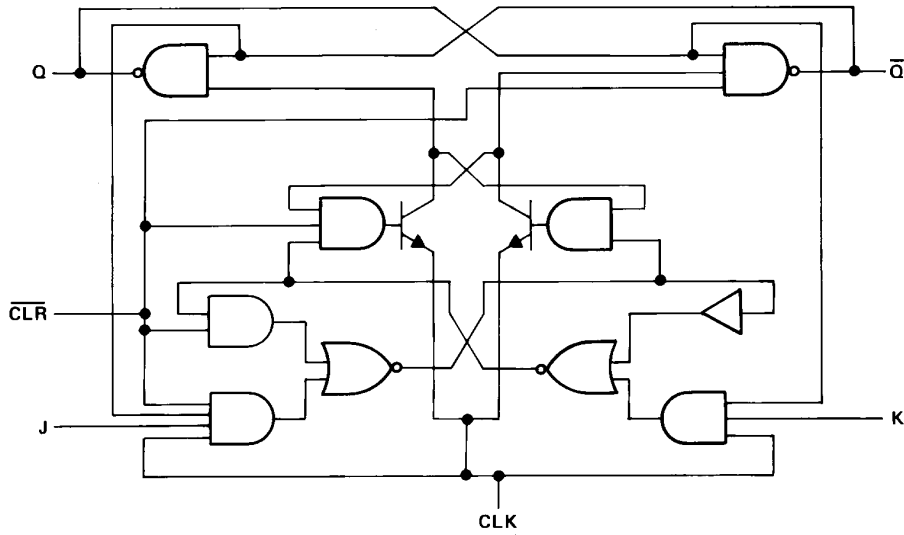
**SN74107, SN74LS107A,
SN74107, SN74LS107A
DUAL J-K FLIP-FLOPS WITH CLEAR**

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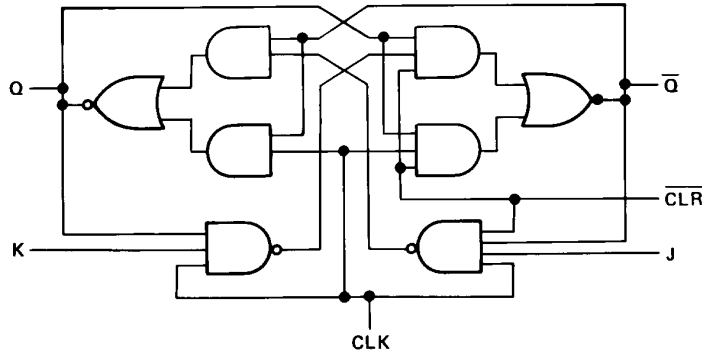
logic diagrams (positive logic)

FIGURE 1 '107 (ALL CAPS LETTERS)

subheading
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'LS107A



2 TTL Devices

TABLE HEADINGS--U

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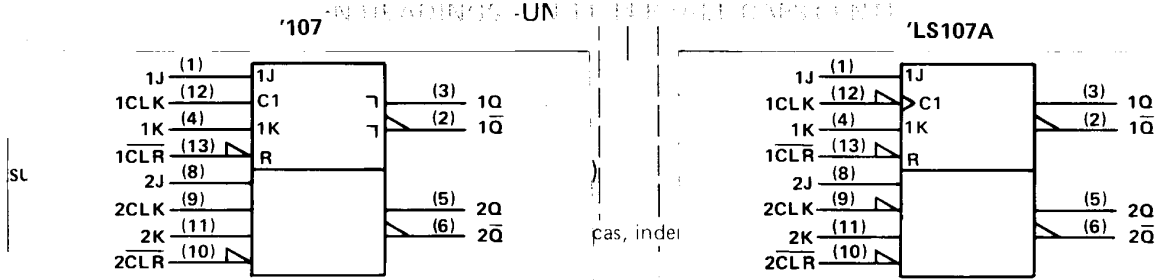
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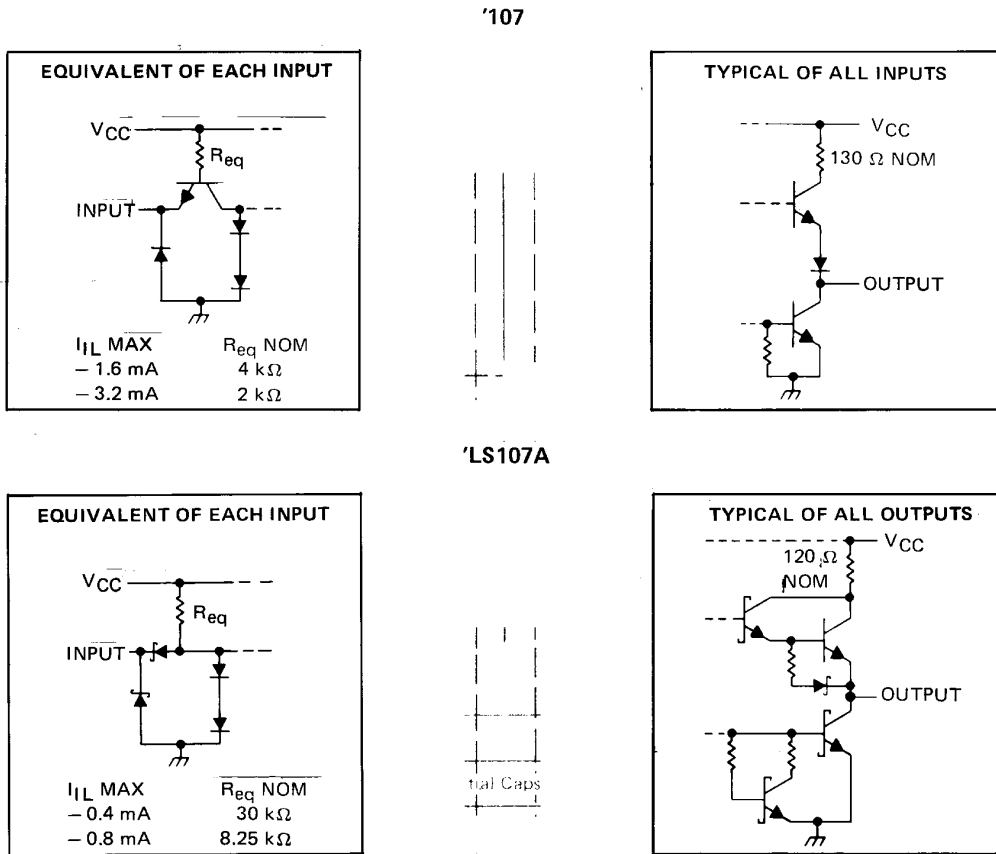
SN54107, SN54LS107A,
SN74107, SN74LS107A
DUAL J-K FLIP-FLOPS WITH CLEAR

logic symbols†



†These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for D, J, and N packages.

schematic of inputs and outputs



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage: '107	5.5 V
'LS107A	7 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

SN54107, SN74107

DUAL J-K FLIP-FLOPS WITH CLEAR

recommended operating conditions

		SN54107			SN74107			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH}	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage				0.8			V
I _{OH}	High-level output current				-0.4			mA
I _{OL}	Low-level output current				16			mA
t _w	Pulse duration	CLK high		20	20		ns	
		CLK low		47	47			
		CLR low		25	25			
t _{su}	Input setup time before CLK †	0			0			ns
t _h	Input hold time-data after CLK †	0			0			ns
T _A	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN54107			SN74107			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -12 mA	-1.5			-1.5			V
V _{OH}	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = 0.8 V, I _{OH} = -0.4 mA	2.4	3.4		2.4	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = 0.8 V, I _{OL} = 16 mA		0.2	0.4		0.2	0.4	V
I _I	V _{CC} = MAX, V _I = 5.5 V	1			1			mA
I _{IH}	J or K	40			40			μA
	All other	80			80			
I _{IL}	J or K	-1.6			-1.6			mA
	All other	-3.2			-3.2			
I _{OS} §	V _{CC} = MAX	-20		-57	-18		-57	mA
I _{CC} ¶	V _{CC} = MAX, See Note 2		10	20		10	20	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25° C.

§ Not more than one output should be shorted at a time.

¶ Average per flip-flop.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \bar{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, V_{CC} = 5 V, T_A = 25° C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max}			R _L = 400 Ω, C _L = 15 pF	15	20		MHz
t _{PLH}	CLR	\bar{Q}			16	25	ns
t _{PHL}		Q			25	40	ns
t _{PLH}	CLK	Q or \bar{Q}			16	25	ns
t _{PHL}						25	40

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

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SN54LS107A, SN74LS107A DUAL J-K FLIP-FLOPS WITH CLEAR

recommended operating conditions

		SN54LS107A			SN74LS107A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH}	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.7			0.8	V
I _{OH}	High-level output current			-0.4			-0.4	mA
I _{OL}	Low-level output current			4			8	mA
f _{clock}	Clock frequency	0		30	0		30	MHz
t _w	Pulse duration	CLK high		20			20	ns
		CLR low		25			25	
t _{su}	Setup time before CLK ↓	data high or low		20			20	ns
		CLR inactive		25			25	
t _h	Hold time-data after CLK ↓			0			0	ns
T _A	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†	SN54LS107A			SN74LS107A			UNIT	
			MIN	TYP‡	MAX	MIN	TYP‡	MAX		
V _{IK}		V _{CC} = MIN, I _I = -18 mA			-1.5			-1.5	V	
V _{OH}		V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = MAX, I _{OH} = -0.4 mA	2.5	3.4		2.7	3.4		V	
V _{OL}		V _{CC} = MIN, V _{IL} = MAX, V _{IH} = 2 V, I _{OL} = 4 mA		0.25	0.4		0.25	0.4	V	
		V _{CC} = MIN, V _{IL} = MAX, V _{IH} = 2 V, I _{OL} = 8 mA					0.35	0.5		
I _I	J or K	V _{CC} = MAX, V _I = 7 V			0.1			0.1	mA	
	CLR				0.3			0.3		
	CLK				0.4			0.4		
I _{IH}	J or K	V _{CC} = MAX, V _I = 2.7 V			20			20	μA	
	CLR				60			60		
	CLK				80			80		
I _{IL}	J or K	V _{CC} = MAX, V _I = 0.4 V			-0.4			-0.4	mA	
	CLR or CLK				-0.8			-0.8		
I _{OS} §		V _{CC} = MAX, See Note 4	-20		-100		-20		-100	mA
I _{CC} (Total)		V _{CC} = MAX, See Note 2		4	6		4	6	mA	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \bar{Q} , outputs high in turn. At the time of measurement, the clock input is grounded.

NOTE 4: For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V_O = 2.25 V and 2.125 V for the 54 family and the 74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
f _{max}					30	45		MHz
t _{PLH}	$\overline{\text{CLR}}$ or CLK	Q or \bar{Q}	R _L = 2 kΩ,	C _L = 15 pF		15	20	ns
t _{PHL}						15	20	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

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